

7th Beam Telescopes and Test Beams Workshop



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Beam generation for test beams

Monday, 14 January 2019 14:00 (45 minutes)

The presentation introduces the concepts of the secondary and tertiary beams for the use as test beams. It describes the generation of the test beams by interaction of primary or secondary beam with e.g. a target, converter, radiator or absorber and explains the parameters of particle production. The design of secondary and tertiary beamlines is presented, including the methods for selection of particle type and beam energy, as well as for the manipulation of beam parameters such as beam size, divergence, intensity etc. An overview of the common beam diagnostic tools and their functionality is given. Finally, the specifics of the beam generation and equipment at CERN are briefly discussed.

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